Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/811 306	CHANG SHIH-VIIAN

Examiner

Anabel M. Ton

CHANG, SHIH-YUAN
Art Unit

2875

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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